

WHAT IS CLAIMED IS:

1. A probe card, comprising:
a circuit board for sending and receiving electrical signals to test the operation of semiconductor integrated circuits;
a probe needle with one end connected to said circuit board and the other end coming into contact with electrodes connected to said semiconductor integrated circuit; and
a circuit for applying voltage to said probe needle to destroy insulating film at the tip of said probe needle.
2. A testing apparatus for semiconductor integrated circuits, comprising the probe card according to Claim 1.